

INSPECTION SYSTEM AND METHOD USING EDDY CURRENT SENSOR ARRAY

ABSTRACT

A sensor system may include a sensor array comprising a plurality of eddy current sensor elements, the sensor array having a contact side and a mounting side opposite the contact side. The sensor system may include a sensor mount coupled to the mounting side of the sensor array. The sensor system may include a biasing element configured to bias the contact side of the sensor array against an inspected surface of a component and secure the sensor array to the component while the inspected surface moves relative to the sensor array during data capture.

[Figure 1]